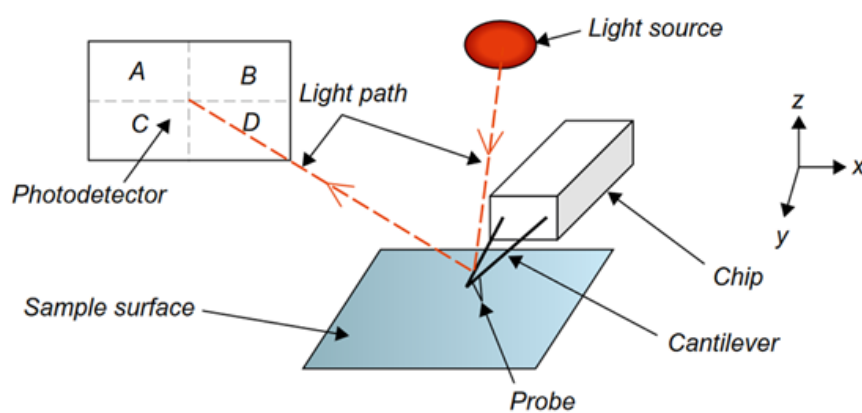
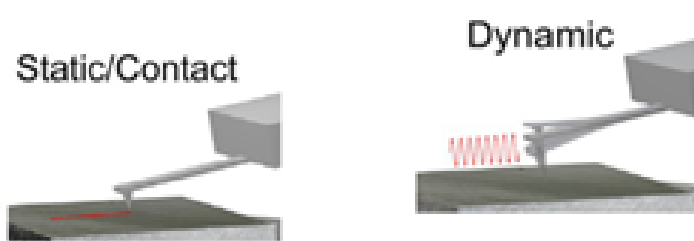


ATOMIC FORCE MICROSCOPY



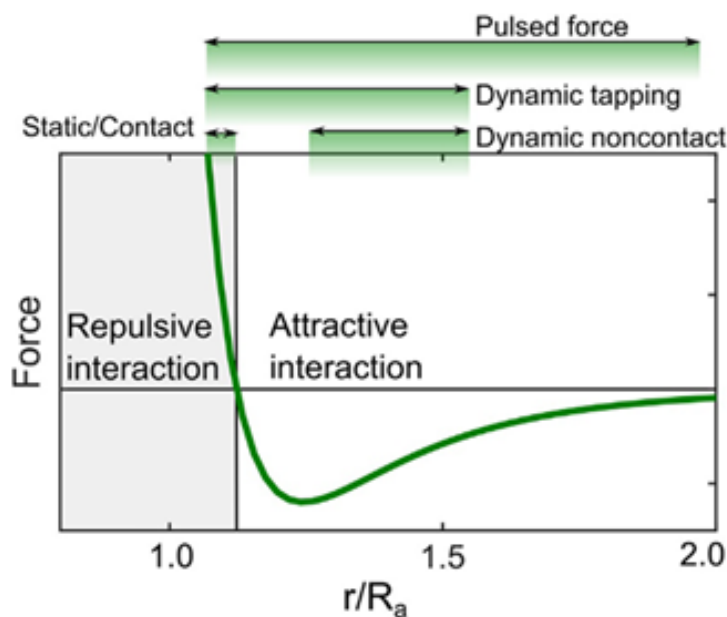
1. AFM

AFM was invented in 1986. AFM allows to obtain surface topography of the sample surface through detecting force between the tip of the cantilever and the sample surface.



2. STATIC/CONTACT MODE

- Also known as contact mode
- Tip is continuously in contact with sample surface
- Focus on Repulsive force
- Suitable for relatively flat and stiff surfaces



3. DYNAMIC MODE

- Also known as non-contact mode
- Cantilever oscillate at intermittent contact
- Reduce frictional and lateral forces between tip and surface
- Suitable for soft surfaces such as biological samples

4. REFERENCE ARTICLES

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